



SECOND INTERNATIONAL NANOTECHNOLOGY CONFERENCE ON COMMUNICATIONS AND COOPERATION

Speaker's Biography

Dr. Michael T. Postek, NIST

Dr. Michael T. Postek is the Assistant to the Director for Nanotechnology and Chair of the NIST Nanotechnology Strategic Working Group. He is also the Acting Division Chief of the Precision Engineering Division and the Leader of the Nano-scale Metrology Group and Program Manager of the Nanomanufacturing Program in the Manufacturing Engineering Laboratory at the National Institute of Standards and Technology (NIST). Dr. Postek is both a nationally and internationally recognized expert in scanning electron microscope (SEM) critical dimension (CD) metrology with that instrumentation.

Dr. Postek's current research areas include nanotechnology and nanometrology. He has been involved with electron microscopy for over 30 years and micro and nano-scale scanning electron microscope-based length metrology for over 20 years and has published over 180 papers, articles and book chapters on this and related topics. He is a charter member of the International SEMATECH Advanced Metrology Advisory Group and a contributor to the International Technology Roadmap for Semiconductors. His work centers on improvements in SEM relative to nanotechnology and semiconductor related metrology. Among his credits are: 2005 Nano 50 Award, NIST bronze medal, three Department of Commerce/NIST silver medals, 1998 R&D 100 Award, Federal Laboratory Consortium Award for Technology Transfer and NIST top 100 papers Award 2000.

Dr Postek received his B. A. from the University of South Florida (1973); M. S. from Texas A&M University (1974); Ph.D. from Louisiana State University (1980) and an Executive M. S. in Technology Management from the University of Maryland (1997).